

CENTRE FOR MATERIALS FOR ELECTRONICS TECHNOLOGY (C-MET)

(Scientific Society, Ministry of Electronics & Information Technology, Govt. of India)
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ENQUIRY LETTER

ENQUIRY NO. HD/PUR/SP-35/SCW/06/2016-17/ 8672

Date: 23.12.2016

To

Subject: Procurement of Single Crystal Wafers - regarding

	12.01.2017	TIME BY:15.30 hours [IST]	
-	Due date for receipt of the quotations	12.01.2017	

Sir.

Sealed quotations conforming to the specifications are invited for the following item/s:-

S. No.	Description of the item	Qty	Specifications
01	2" 6H SIc Single Crystal Wafer (As per Specifications attached)	40	Pl. see Annexure enclosed
02	2" Semi-insulating (SI) - 6H-SiC Single Crystal Wafer (as per Specifications attached)	10	

The envelope, superscribed as under should be sent to the undersigned:-

QUOTATION NO.	
DUE DATE	
ITEM	

Quotation may please be submitted, keeping in view, the terms and conditions overleaf, otherwise quotations will be rejected.

Note: (i) Firms or their authorized representatives are requested to attend the opening of Combined/Technical bids after closing time i.e. on 12th January, 2017 at 15:45 hours.

Note: If there is any delay in opening of technical bids will be intimated to all bidders.

(ii) The Technical & Financial bids should be in separate sealed covers

(iii) Delivery period should be within 8 weeks from the date of Supply Order

(iv) These details are also available in our website: http://www.cmet.gov.in

Thanking you,

Yours faithfully,

(A. LAKSHMI VASUDHA)
Administrative Officer (A)
lakshmi@cmet.gov.in

SPECIFICATIONS OF SEMI-INSULATING SI 6H SiC SINGLE CRYSTAL SUBSTRATE

Sl. No	Sic Wafer Properties	Specifications	
-1.	SiC wafer type (Polytype)	Semi-insulating (SI) 6H SiC	
2.	Bandgap	3.0 eV	
3.	Diameter	2" (inch)	
4.	Quantity	10 no.	
5.	Conductivity Type	SI - type	
6.	Substrate thickness	≥ 325 ± 25 µm	
7.	Packing	Single wafer	
8.	Full Width Half Maxima (FWHM)	< 30 arc-sec	
9.	Micropipe density (MPD)	< 10 cm ⁻²	
10.	Orientation	Off axis: 3.5° towards $<11-20> \pm 0.5^{\circ}$	
		/ On-axis: $<0001>\pm0.5^{\circ}$	
11.	Surface finish	Double side polished: a) One side:- C-face - CMP, Epi-ready (Preferred) b) Other side:- Si-face - optical polish / CMP	
12.	Surface Roughness	Ra < 2 nm	
13.	Resistivity	> 1E5 Ohm-cm	

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SPECIFICATIONS OF 6H N-SiC SINGLE CRYSTAL SUBSTRATE

Sl. No Sic Wafer Properties		Specifications	
1.	SiC wafer type (Polytype)	6H SiC	
2.	Bandgap	3.0 eV	
3.	Diameter	2" (inch)	
4.	Quantity	40 no.	
5.	Conductivity Type	N - type	
6.	Substrate thickness	\geq 325 \pm 25 μm	
7,	Packing	Single wafer	
8.	Full Width Half Maxima (FWHM)	< 30 arc-sec	
9.	Micropipe density (MPD)	< 10 cm ⁻²	
10.	Orientation	Off axis: 3.5° towards $<11-20> \pm 0.5^{\circ}$	
11.	Surface finish	Double side polished:— a) One side:- C-face - CMP, Epi-ready (Preferred) b) Other side:- Si-face - optical polish / CMP	
12.	Surface Roughness	Ra < 2 nm	
13.	Resistivity	> 0.05 Ohm-cm	

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